

**Search Notes**

Application/Control No.

10/506,689

Examiner

Ibrahim A. Khan

Applicant(s)/Patent under  
Reexamination

NIWANO, KAZUHITO

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
370	347	4/14/2007	IAK
370	331	4/14/2007	IAK
455	442	4/14/2007	IAK
455	10	4/14/2007	IAK
455	13.4	4/14/2007	IAK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EASTImage and keyword search in USPAT, US-PGPUB, DERWENT, EPO, IBM_TDB (see attached search strategy)	4/14/2007	IAK